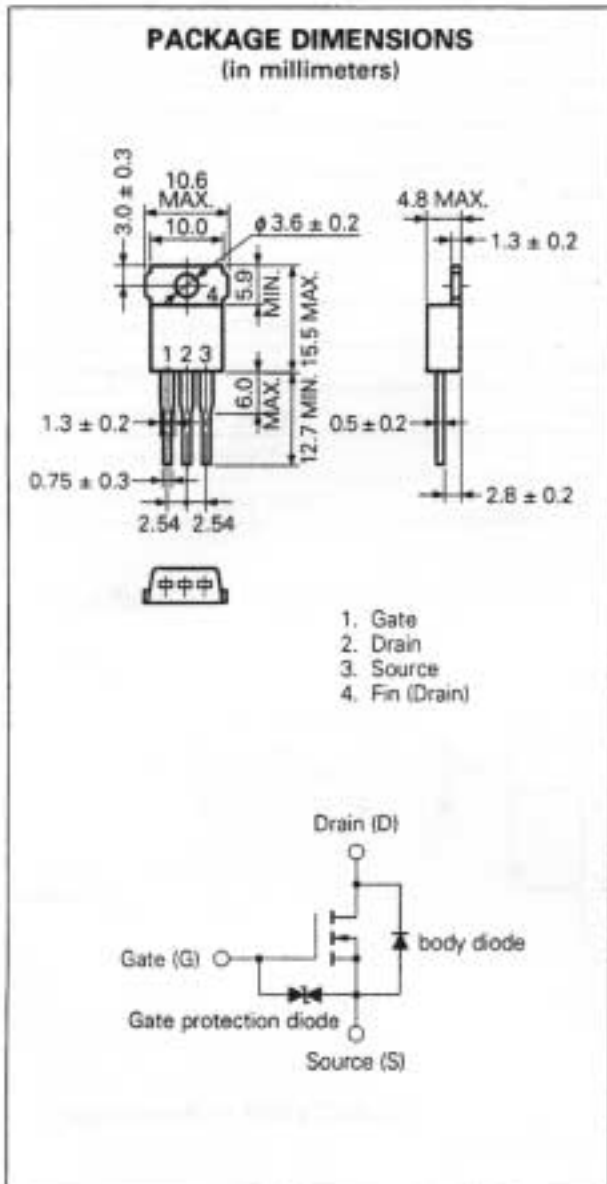


N-CHANNEL MOS FIELD EFFECT POWER TRANSISTOR
2SK1287

SWITCHING
 N-CHANNEL POWER MOS FET
 INDUSTRIAL USE



DESCRIPTION

The 2SK1287 is N-channel MOS Field Effect Transistor designed for solenoid, motor and lamp driver.

FEATURES

- Low On-state Resistance
 $R_{DS(on)} \leq 70 \text{ m}\Omega \text{ MAX. (} V_{GS} = 10 \text{ V, } I_D = 10 \text{ A)}$
 $R_{DS(on)} \leq 95 \text{ m}\Omega \text{ MAX. (} V_{GS} = 4 \text{ V, } I_D = 10 \text{ A)}$
- Low C_{iss} $C_{iss} = 1400 \text{ pF TYP.}$
- Built-in G-S Gate Protection Diodes

QUALITY GRADE

Standard

Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

ABSOLUTE MAXIMUM RATINGS

Maximum Temperatures

Storage Temperature	-55 to +150	°C
Channel Temperature	150	°C MAX.

Maximum Power Dissipation

Total Power Dissipation ($T_a = 25 \text{ }^\circ\text{C}$)	1.5	W
Total Power Dissipation ($T_c = 25 \text{ }^\circ\text{C}$)	60	W

Maximum Voltages and Currents ($T_a = 25 \text{ }^\circ\text{C}$)

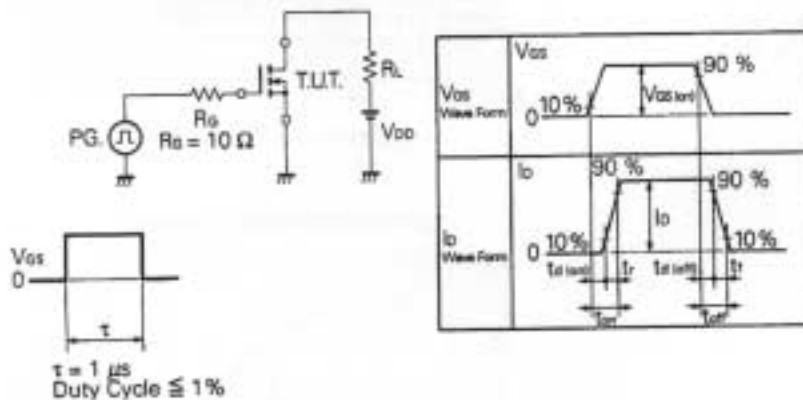
V_{DS}	Drain to Source Voltage	60	V
$V_{GS(A-C)}$	Gate to Source Voltage	± 20	V
$I_{D(DC)}$	Drain Current (DC)	± 15	A
$I_{D(pulse)}^*$	Drain Current (pulse)	± 80	A

* $PW \leq 10 \mu\text{s}$, Duty Cycle $\leq 1 \%$

ELECTRICAL CHARACTERISTICS (T_a = 25 °C)

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS
Drain to Source On-state Resistance	R _{DS(on)}		55	70	mΩ	V _{GS} = 10 V, I _O = 10 A
Drain to Source On-state Resistance	R _{DS(on)}		80	95	mΩ	V _{GS} = 4.0 V, I _O = 10 A
Gate to Source Cutoff Voltage	V _{GS(off)}	1.0		2.5	V	V _{DS} = 10 V, I _O = 1 mA
Forward Transfer Admittance	y _{fs}	7.0	14		S	V _{DS} = 10 V, I _O = 10 A
Drain Leakage Current	I _{DSS}			10	μA	V _{GS} = 60 V, V _{DS} = 0
Gate to Source Leakage Current	I _{GSS}			±10	μA	V _{GS} = ±20 V, V _{DS} = 0
Input Capacitance	C _{iss}		1 400		pF	V _{DS} = 10 V
Output Capacitance	C _{oss}		500		pF	V _{GS} = 0
Reverse Transfer Capacitance	C _{res}		130		pF	f = 1 MHz
Turn-On Delay Time	t _{d(on)}		25		ns	V _{GS(on)} = 10 V
Rise Time	t _r		160		ns	V _{DS} = 30 V
Turn-Off Delay Time	t _{d(off)}		130		ns	I _O = 10 A, R _G = 10 Ω
Fall Time	t _f		80		ns	R _L = 3.0 Ω
Total Gate Charge	Q _G		30		nC	V _{GS} = 10 V
Gate to Source Charge	Q _{GS}		5		nC	I _O = 20 A
Gate to Drain Charge	Q _{GD}		10		nC	V _{DS} = 48 V
Diode Forward Voltage	V _{SD}		1.0		V	I _{SD} = 20 A, V _{GS} = 0
Reverse Recovery Time	t _{rr}		150		ns	I _r = 20 A, V _{GS} = 0
Reverse Recovery Charge	Q _{rr}		250		nC	di/dt = 50 A/μs

Test Circuit 1: Switching Time



Test Circuit 2: Gate Charge

